

DRAM

1 MEG x 4 DRAM

5V, FAST PAGE MODE, OPTIONAL
EXTENDED REFRESH

FEATURES

- 1,024-cycle refresh distributed across 16ms (MT4C4001J) or 128ms (MT4C4001J L)
- Industry-standard pinout, timing, functions and packages
- High-performance CMOS silicon-gate process
- Single +5V $\pm 10\%$ power supply
- All inputs, outputs and clocks are TTL-compatible
- Refresh modes: $\overline{\text{RAS}}$ ONLY, $\overline{\text{CAS}}$ -BEFORE- $\overline{\text{RAS}}$ (CBR), HIDDEN; optional Extended
- FAST PAGE MODE access cycle
- Low power, 0.8mW standby; 225mW active, typical (MT4C4001J L)

OPTIONS

- Timing
 - 60ns access -6
 - 70ns access -7
- Packages
 - Plastic SOJ (300 mil) DJ
 - Plastic TSOP (300 mil) TG
- Refresh Rate
 - Standard 16ms period None
 - Extended 128ms period L
- Part Number Example: MT4C4001JDJ-6 L

MARKING

KEY TIMING PARAMETERS

SPEED	t_{RC}	t_{RAC}	t_{PC}	t_{AA}	t_{CAC}	t_{RP}
-6	110ns	60ns	35ns	30ns	15ns	40ns
-7	130ns	70ns	40ns	35ns	20ns	50ns

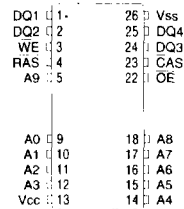
GENERAL DESCRIPTION

The MT4C4001J(L) is a randomly accessed solid-state memory containing 4,194,304 bits organized in a x4 configuration. $\overline{\text{RAS}}$ is used to latch the first 10 bits and $\overline{\text{CAS}}$ the latter 10 bits. READ and WRITE cycles are selected with the $\overline{\text{WE}}$ input. A logic HIGH on $\overline{\text{WE}}$ dictates READ mode while a logic LOW on $\overline{\text{WE}}$ dictates WRITE mode. During a WRITE cycle, data-in (D) is latched by the falling edge of $\overline{\text{WE}}$ or $\overline{\text{CAS}}$, whichever occurs last. If $\overline{\text{WE}}$ goes LOW prior to $\overline{\text{CAS}}$ going LOW, the output pins remain open (High-Z) until the next $\overline{\text{CAS}}$ cycle.

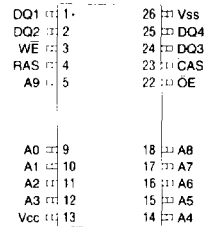
If $\overline{\text{WE}}$ goes LOW after data reaches the output pins, data-out (Q) is activated and retains the selected cell data as long

PIN ASSIGNMENT (Top View)

20/26-Pin SOJ (DA-1)



20/26-Pin TSOP (DB-1)



as $\overline{\text{CAS}}$ remains LOW (regardless of $\overline{\text{WE}}$ or $\overline{\text{RAS}}$). This late $\overline{\text{WE}}$ pulse results in a READ WRITE cycle. The four data inputs and four data outputs are routed through four pins using common I/O and pin direction is controlled by $\overline{\text{WE}}$ and $\overline{\text{OE}}$.

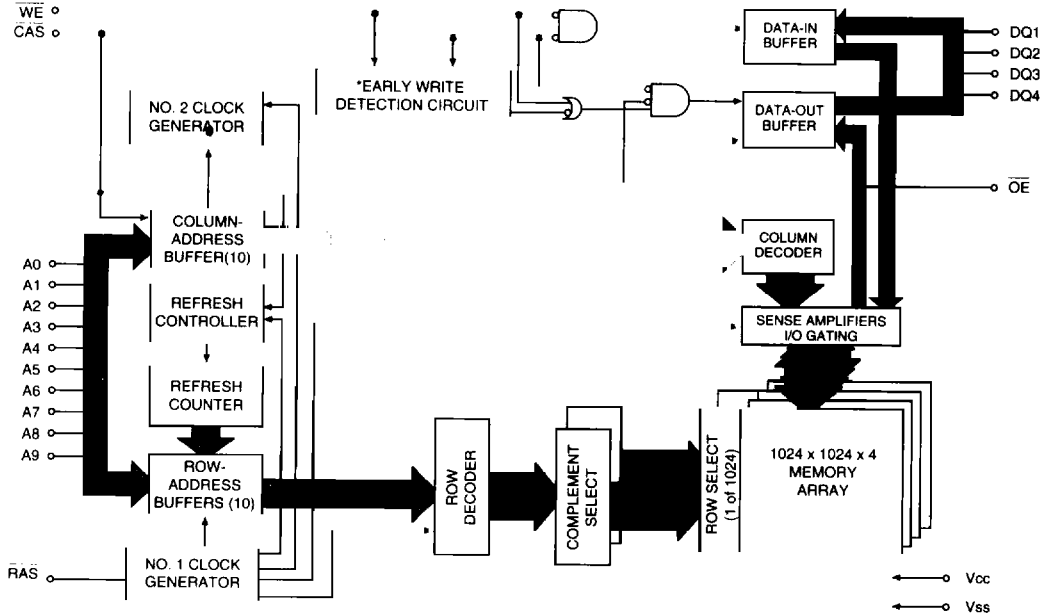
FAST PAGE MODE

FAST PAGE MODE operations allow faster data operations (READ, WRITE or READ-MODIFY-WRITE) within a row-address-defined page boundary. The FAST PAGE MODE cycle is always initiated with a row-address strobed-in by $\overline{\text{RAS}}$ followed by a column-address strobed-in by $\overline{\text{CAS}}$. $\overline{\text{CAS}}$ may be toggled-in by holding $\overline{\text{RAS}}$ LOW and strobing-in different column-addresses, thus executing faster memory cycles. Returning $\overline{\text{RAS}}$ HIGH terminates the FAST PAGE MODE operation.

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FUNCTIONAL BLOCK DIAGRAM
FAST PAGE MODE

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***NOTE:** 1. If \overline{WE} goes LOW prior to \overline{CAS} going LOW, EW detection circuit output is a HIGH (EARLY WRITE).
2. If \overline{CAS} goes LOW prior to \overline{WE} going LOW, EW detection circuit output is a LOW (LATE WRITE).

TRUTH TABLE

FUNCTION		RAS	CAS	WE	OE	ADDRESSES		DATA-IN/OUT
						'R	'C	DQ1-DQ4
Standby		H	H→X	X	X	X	X	High-Z
READ		L	L	H	L	ROW	COL	Data-Out
EARLY WRITE		L	L	L	X	ROW	COL	Data-In
READ WRITE		L	L	H→L	L→H	ROW	COL	Data-Out, Data-In
FAST-PAGE-MODE	1st Cycle	L	H→L	H	L	ROW	COL	Data-Out
READ	2nd Cycle	L	H→L	H	L	n/a	COL	Data-Out
FAST-PAGE-MODE	1st Cycle	L	H→L	L	X	ROW	COL	Data-In
EARLY-WRITE	2nd Cycle	L	H→L	L	X	n/a	COL	Data-In
FAST-PAGE-MODE	1st Cycle	L	H→L	H→L	L→H	ROW	COL	Data-Out, Data-In
READ-WRITE	2nd Cycle	L	H→L	H→L	L→H	n/a	COL	Data-Out, Data-In
RAS-ONLY REFRESH		L	H	X	X	ROW	n/a	High-Z
HIDDEN	READ	L→H→L	L	H	L	ROW	COL	Data-Out
REFRESH	WRITE	L→H→L	L	L	X	ROW	COL	Data-In
CBR REFRESH		H→L	L	H	X	X	X	High-Z

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ABSOLUTE MAXIMUM RATINGS*

Voltage on Any Pin Relative to V _{SS}	-1V to +7V
Operating Temperature, T _A (ambient)	0°C to +70°C
Storage Temperature (plastic).....	-55°C to +150°C
Power Dissipation	1W
Short Circuit Output Current	50mA

*Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

ELECTRICAL CHARACTERISTICS AND RECOMMENDED DC OPERATING CONDITIONS

(Notes: 1, 5, 6) (V_{CC} = +5V ±10%)

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PARAMETER/CONDITION	SYMBOL	MIN	MAX	UNITS	NOTES
Supply Voltage	V _{CC}	4.5	5.5	V	
Input High (Logic 1) Voltage, all inputs	V _{IH}	2.4	V _{CC} +1	V	
Input Low (Logic 0) Voltage, all inputs	V _{IL}	-1.0	0.8	V	
INPUT LEAKAGE CURRENT					
Any input 0V ≤ V _{IN} ≤ V _{CC} +1V (All other pins not under test = 0V)	I _I	-2	2	μA	
OUTPUT LEAKAGE CURRENT (Q is disabled; 0V ≤ V _{OUT} ≤ 5.5V)	I _{OZ}	-10	10	μA	
OUTPUT LEVELS					
Output High Voltage (I _{OUT} = -5mA)	V _{OH}	2.4		V	
Output Low Voltage (I _{OUT} = 4.2mA)	V _{OL}		0.4	V	

PARAMETER/CONDITION	SYMBOL	MAX		UNITS	NOTES
		-6	-7		
STANDBY CURRENT: (TTL) ($\overline{RAS} = \overline{CAS} = V_{IH}$)	I _{CC1}	2	2	mA	
STANDBY CURRENT: (CMOS) ($\overline{RAS} = \overline{CAS} = V_{CC} - 0.2V$)	I _{CC2}	1	1	mA	
	I _{CC2} (L only)	200	200	μA	
OPERATING CURRENT: Random READ/WRITE Average power supply current ($\overline{RAS}, \overline{CAS}$, single address cycling; $t_{RC} = t_{RC} [MIN]$)	I _{CC3}	110	100	mA	3, 28
OPERATING CURRENT: FAST PAGE MODE Average power supply current ($\overline{RAS} = V_{IL}, \overline{CAS}$, address cycling; $t_{PC} = t_{PC} [MIN]$)	I _{CC4}	80	70	mA	3, 28
REFRESH CURRENT: \overline{RAS} ONLY Average power supply current (\overline{RAS} cycling, $\overline{CAS} = V_{IH}$; $t_{RC} = t_{RC} [MIN]$)	I _{CC5}	110	100	mA	3, 28
REFRESH CURRENT: CBR Average power supply current ($\overline{RAS}, \overline{CAS}$, address cycling; $t_{RC} = t_{RC} [MIN]$)	I _{CC6}	110	100	mA	3, 4
REFRESH CURRENT: Extended (L version only) Average power supply current during Extended Refresh: $\overline{CAS} = 0.2V$ or CBR cycling; $\overline{RAS} = t_{RAS} [MIN]$; $\overline{WE} = V_{CC} - 0.2V$; \overline{OE}, A_0-A_9 and $D_{IN} = V_{CC} - 0.2V$ or $0.2V$; (D_{IN} may be left open); $t_{RC} = 125\mu s$ (1,024 rows at $125\mu s = 128ms$)	I _{CC7} (L only)	300	300	μA	3, 4, 26

CAPACITANCE

PARAMETER	SYMBOL	MIN	MAX	UNITS	NOTES
Input Capacitance: A0-A9	C _{I1}		5	pF	2
Input Capacitance: \overline{RAS} , \overline{CAS} , \overline{WE} , \overline{OE}	C _{I2}		7	pF	2
Input/Output Capacitance: DQ	C _{I0}		7	pF	2

ELECTRICAL CHARACTERISTICS AND RECOMMENDED AC OPERATING CONDITIONS

(Notes: 5, 6, 7, 8, 9, 10, 11, 12, 22) (V_{CC} = +5V ±10%)

AC CHARACTERISTICS PARAMETER	SYM	-6		-7		UNITS	NOTES
		MIN	MAX	MIN	MAX		
Access time from column-address	t _{AA}		30		35	ns	
Column-address hold time (referenced to \overline{RAS})	t _{AR}	45		50		ns	
Column-address setup time	t _{ASC}	0		0		ns	
Row-address setup time	t _{ASR}	0		0		ns	
Column-address to \overline{WE} delay time	t _{AWD}	55		65		ns	20
Access time from \overline{CAS}	t _{CAC}		15		20	ns	14
Column-address hold time	t _{CAH}	10		15		ns	
\overline{CAS} pulse width	t _{CAS}	15	10,000	20	10,000	ns	
\overline{CAS} hold time (CBR REFRESH)	t _{CHR}	10		10		ns	4
\overline{CAS} to output in Low-Z	t _{CLZ}	0		0		ns	
\overline{CAS} precharge time	t _{CP}	10		10		ns	15
Access time from \overline{CAS} precharge	t _{CPA}		35		40	ns	
\overline{CAS} to \overline{RAS} precharge time	t _{CRP}	10		10		ns	
\overline{CAS} hold time	t _{CSH}	60		70		ns	
\overline{CAS} setup time (CBR REFRESH)	t _{CSR}	10		10		ns	4
\overline{CAS} to \overline{WE} delay time	t _{CWD}	40		50		ns	20
Write command to \overline{CAS} lead time	t _{CWL}	15		20		ns	
Data-in hold time	t _{DH}	10		15		ns	21
Data-in hold time (referenced to \overline{RAS})	t _{DHR}	45		55		ns	
Data-in setup time	t _{DS}	0		0		ns	21
Output disable	t _{OD}	3	15	3	20	ns	25, 27
Output enable	t _{OE}		15		20	ns	22
\overline{OE} hold time from \overline{WE} during READ-MODIFY-WRITE cycle	t _{OEH}	15		20		ns	24
Output buffer turn-off delay	t _{OFF}	3	15	3	20	ns	19, 27
\overline{OE} setup prior to \overline{RAS} during HIDDEN REFRESH cycle	t _{ORD}	0		0		ns	
FAST-PAGE-MODE READ or WRITE cycle time	t _{PC}	35		40		ns	
FAST-PAGE-MODE READ-WRITE cycle time	t _{PRWC}	85		100		ns	
Access time from \overline{RAS}	t _{RAC}		60		70	ns	13
\overline{RAS} to column-address delay time	t _{RAD}	15	30	15	35	ns	17

ELECTRICAL CHARACTERISTICS AND RECOMMENDED AC OPERATING CONDITIONS

(Notes: 5, 6, 7, 8, 9, 10, 11, 12, 22) ($V_{CC} = +5V \pm 10\%$)

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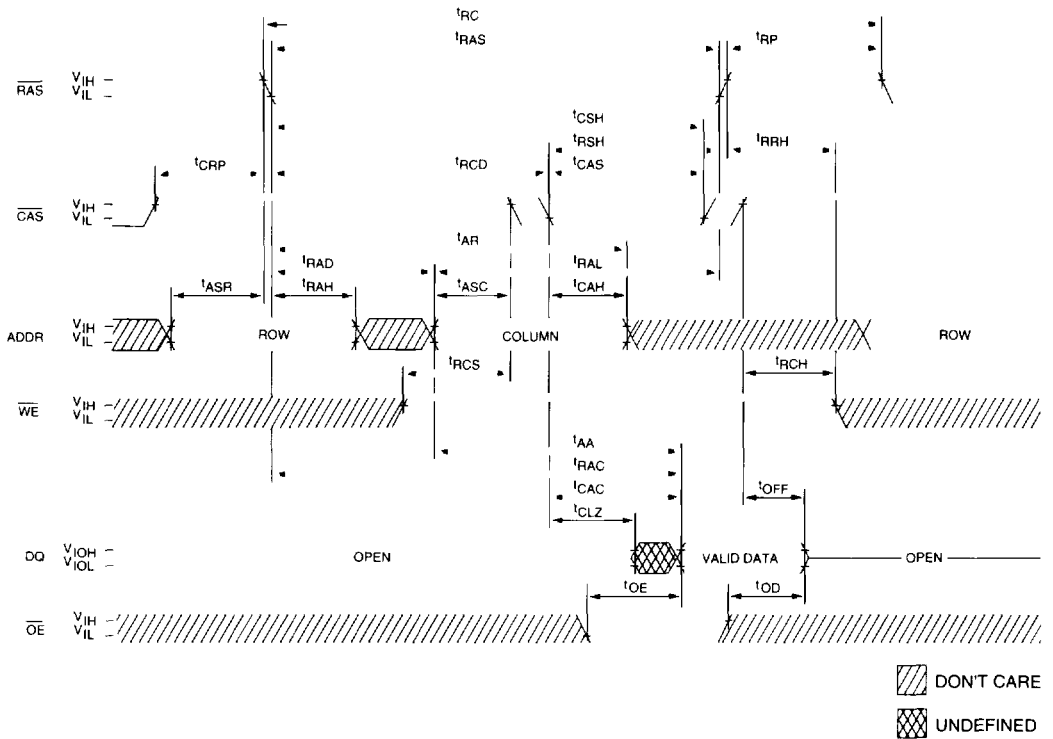
AC CHARACTERISTICS PARAMETER	SYM	-6		-7		UNITS	NOTES
		MIN	MAX	MIN	MAX		
Row-address hold time	t_{RAH}	10		10		ns	
Column-address to \overline{RAS} lead time	t_{RAL}	30		35		ns	
\overline{RAS} pulse width	t_{RAS}	60	10,000	70	10,000	ns	
\overline{RAS} pulse width (FAST PAGE MODE)	t_{RASP}	60	100,000	70	100,000	ns	
Random READ or WRITE cycle time	t_{RC}	110		130		ns	
\overline{RAS} to \overline{CAS} delay time	t_{RCD}	20	45	20	50	ns	16
Read command hold time (referenced to \overline{CAS})	t_{RCH}	0		0		ns	18
Read command setup time	t_{RCS}	0		0		ns	
Refresh period (1,024 cycles)	t_{REF}		16		16	ms	
Refresh period (1,024 cycles) L version	t_{REF}		128		128	ms	
\overline{RAS} precharge time	t_{RP}	40		50		ns	
\overline{RAS} to \overline{CAS} precharge time	t_{RPC}	0		0		ns	
Read command hold time (referenced to \overline{RAS})	t_{RRH}	0		0		ns	18
\overline{RAS} hold time	t_{RSH}	15		20		ns	
READ WRITE cycle time	t_{RWC}	150		180		ns	
\overline{RAS} to \overline{WE} delay time	t_{RWD}	90		100		ns	20
Write command to \overline{RAS} lead time	t_{RWL}	15		20		ns	
Transition time (rise or fall)	t_T	3	50	3	50	ns	
Write command hold time	t_{WCH}	10		15		ns	
Write command hold time (referenced to \overline{RAS})	t_{WCR}	45		55		ns	
\overline{WE} command setup time	t_{WCS}	0		0		ns	20
Write command pulse width	t_{WP}	10		15		ns	
\overline{WE} hold time (CBR REFRESH)	t_{WRH}	10		10		ns	
\overline{WE} setup time (CBR REFRESH)	t_{WRP}	10		10		ns	

NOTES

1. All voltages referenced to V_{SS}.
2. This parameter is sampled. V_{CC} = +4.5V; f = 1 MHz.
3. I_{CC} is dependent on output loading and cycle rates. Specified values are obtained with minimum cycle time and the outputs open.
4. Enables on-chip refresh and address counters.
5. The minimum specifications are used only to indicate cycle time at which proper operation over the full temperature range is assured.
6. An initial pause of 100μs is required after power-up followed by eight RAS refresh cycles (RAS ONLY or CBR with WE HIGH) before proper device operation is assured. The eight RAS cycle wake-ups should be repeated any time the REF refresh requirement is exceeded.
7. AC characteristics assume $t_T = 5ns$.
8. V_{IH} (MIN) and V_{IL} (MAX) are reference levels for measuring timing of input signals. Transition times are measured between V_{IH} and V_{IL}. (or between V_{IL} and V_{IH}).
9. In addition to meeting the transition rate specification, all input signals must transit between V_{IH} and V_{IL}. (or between V_{IL} and V_{IH}) in a monotonic manner.
10. If $\overline{CAS} = V_{IH}$, data output is High-Z.
11. If $\overline{CAS} = V_{IL}$, data output may contain data from the last valid READ cycle.
12. Measured with a load equivalent to two TTL gates and 100pF.
13. Assumes that $t_{RCD} < t_{RCD} (MAX)$. If t_{RCD} is greater than the maximum recommended value shown in this table, t_{RAC} will increase by the amount that t_{RCD} exceeds the value shown.
14. Assumes that $t_{RCD} \geq t_{RCD} (MAX)$.
15. If \overline{CAS} is LOW at the falling edge of RAS, Q will be maintained from the previous cycle. To initiate a new cycle and clear the data-out buffer, \overline{CAS} must be pulsed HIGH for 'CP.
16. Operation within the $t_{RCD} (MAX)$ limit ensures that $t_{RAC} (MAX)$ can be met. $t_{RCD} (MAX)$ is specified as a reference point only; if t_{RCD} is greater than the specified $t_{RCD} (MAX)$ limit, then access time is controlled exclusively by 'CAC.
17. Operation within the $t_{RAD} (MAX)$ limit ensures that $t_{RAC} (MIN)$ and $t_{CAC} (MIN)$ can be met. $t_{RAD} (MAX)$ is specified as a reference point only; if t_{RAD} is greater than the specified $t_{RAD} (MAX)$ limit, then access time is controlled exclusively by 'AA.
18. Either 'RCH or 'RRH must be satisfied for a READ cycle.
19. 'OFF (MAX) defines the time at which the output achieves the open circuit condition, and is not referenced to V_{OH} or V_{OL}.
20. 'WCS, 'RWD, 'AWD and 'CWD are not restrictive operating parameters. 'WCS applies to EARLY WRITE cycles. 'RWD, 'AWD and 'CWD apply to READ-MODIFY-WRITE cycles. If $t_{WCS} \geq t_{WCS} (MIN)$, the cycle is an EARLY WRITE cycle and the data output will remain an open circuit throughout the entire cycle. If $t_{RWD} \geq t_{RWD} (MIN)$, $t_{AWD} \geq t_{AWD} (MIN)$ and $t_{CWD} \geq t_{CWD} (MIN)$, the cycle is a READ-MODIFY-WRITE and the data output will contain data read from the selected cell. If neither of the above conditions is met, the state of data-out is indeterminate. \overline{OE} held HIGH and \overline{WE} taken LOW after \overline{CAS} goes LOW results in a LATE WRITE (\overline{OE} -controlled) cycle. 'WCS, 'RWD, 'CWD and 'AWD are not applicable in a LATE WRITE cycle.
21. These parameters are referenced to \overline{CAS} leading edge in EARLY WRITE cycles and \overline{WE} leading edge in LATE WRITE or READ-MODIFY-WRITE cycles.
22. If \overline{OE} is tied permanently LOW, LATE WRITE or READ-MODIFY-WRITE operations are not permissible and should not be attempted.
23. A HIDDEN REFRESH may also be performed after a WRITE cycle. In this case, $\overline{WE} = LOW$ and $\overline{OE} = HIGH$.
24. LATE WRITE and READ-MODIFY-WRITE cycles must have both 'OD and 'OE met (\overline{OE} HIGH during WRITE cycle) in order to ensure that the output buffers will be open during the WRITE cycle. If \overline{OE} is taken back LOW while \overline{CAS} remains LOW, the DQs will remain open.
25. The DQs open during READ cycles once 'OD or 'OFF occur. If \overline{CAS} goes HIGH before \overline{OE} , the DQs will open regardless of the state of \overline{OE} . If \overline{CAS} stays LOW while \overline{OE} is brought HIGH, the DQs will open. If \overline{OE} is brought back LOW (\overline{CAS} still LOW), the DQs will provide the previously read data.
26. Extended refresh current is reduced as 'RAS is reduced from its maximum specification during the extended refresh cycle.
27. The 3ns minimum is a parameter guaranteed by design.
28. Column-address changed once each cycle.

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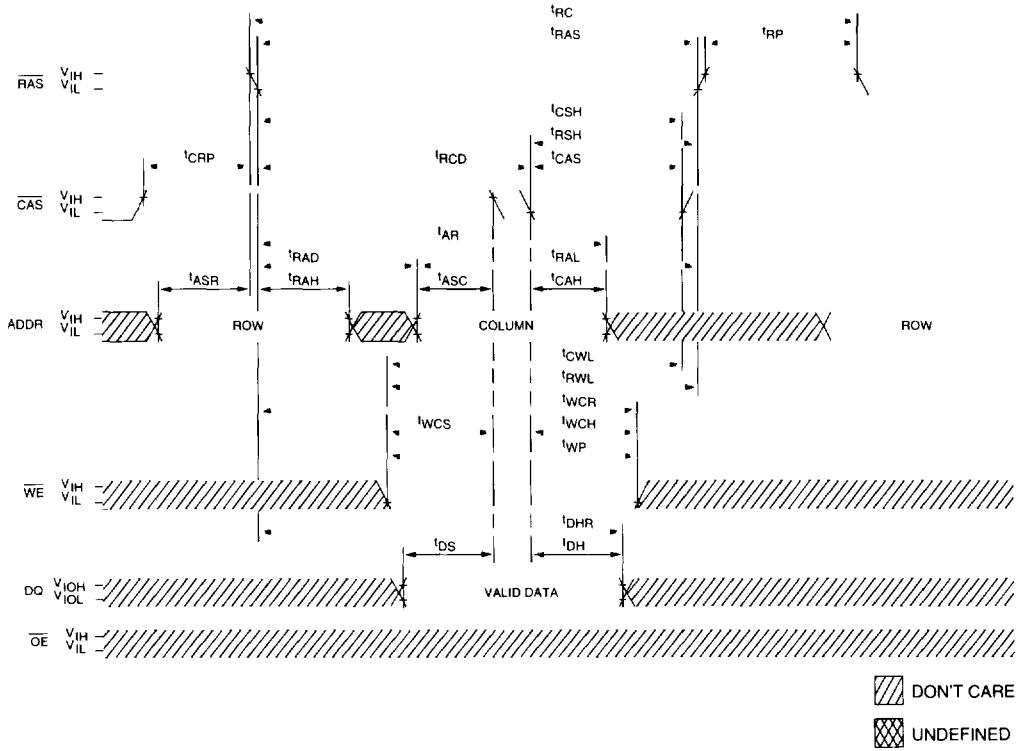
READ CYCLE



TIMING PARAMETERS

SYM	-6		-7		UNITS	SYM	-6		-7		UNITS
	MIN	MAX	MIN	MAX			MIN	MAX	MIN	MAX	
tAA		30		35	ns	tRAC		60		70	ns
tAR	45		50		ns	tRAD	15	30	15	35	ns
tASC	0		0		ns	tRAH	10		10		ns
tASR	0		0		ns	tRAL	30		35		ns
tCAC		15		20	ns	tRAS	60	10,000	70	10,000	ns
tCAH	10		15		ns	tRC	110		130		ns
tCAS	15	10,000	20	10,000	ns	tRCD	20	45	20	50	ns
tCLZ	0		0		ns	tRCH	0		0		ns
tCRP	10		10		ns	tRCS	0		0		ns
tCSH	60		70		ns	tRP	40		50		ns
tOD	3	15	3	20	ns	tRRH	0		0		ns
tOE		15		20	ns	tRSH	15		20		ns
tOFF	3	15	3	20	ns						

EARLY WRITE CYCLE

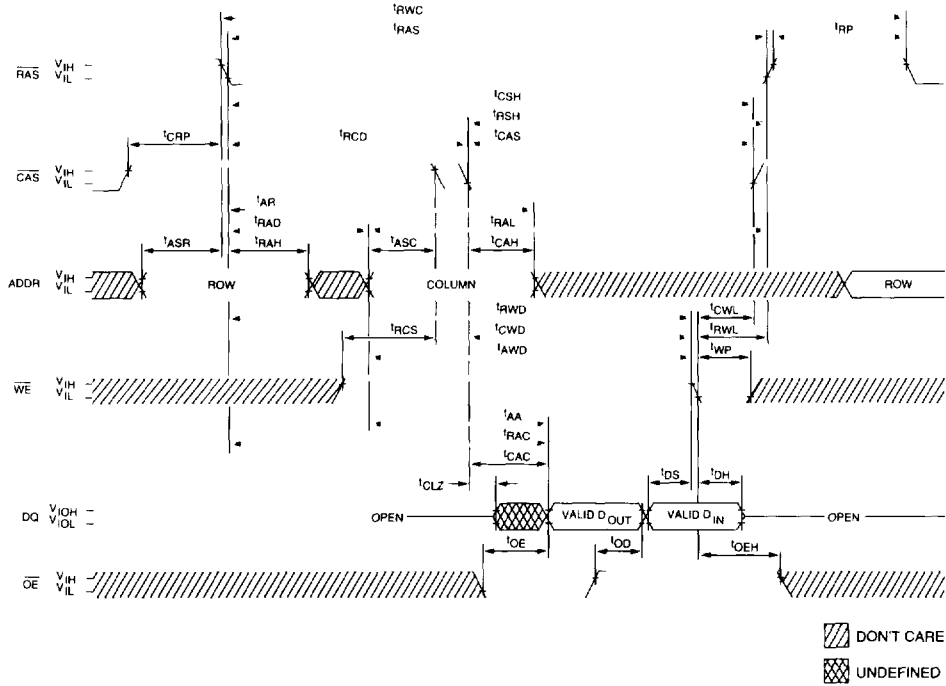


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TIMING PARAMETERS

SYM	-6		-7		UNITS	SYM	-6		-7		UNITS
	MIN	MAX	MIN	MAX			MIN	MAX	MIN	MAX	
tAR	45		50		ns	tRAH	10		10		ns
tASC	0		0		ns	tRAL	30		35		ns
tASR	0		0		ns	tRAS	60	10,000	70	10,000	ns
tCAH	10		15		ns	tRC	110		130		ns
tCAS	15	10,000	20	10,000	ns	tRCD	20	45	20	50	ns
tCRP	10		10		ns	tRP	40		50		ns
tCSH	60		70		ns	tRSH	15		20		ns
tCWL	15		20		ns	tRWL	15		20		ns
tDH	10		15		ns	tWCH	10		15		ns
tDHR	45		55		ns	tWCR	45		55		ns
tDS	0		0		ns	tWCS	0		0		ns
tRAD	15	30	15	35	ns	tWP	10		15		ns

READ WRITE CYCLE
(LATE WRITE and READ-MODIFY-WRITE cycles)

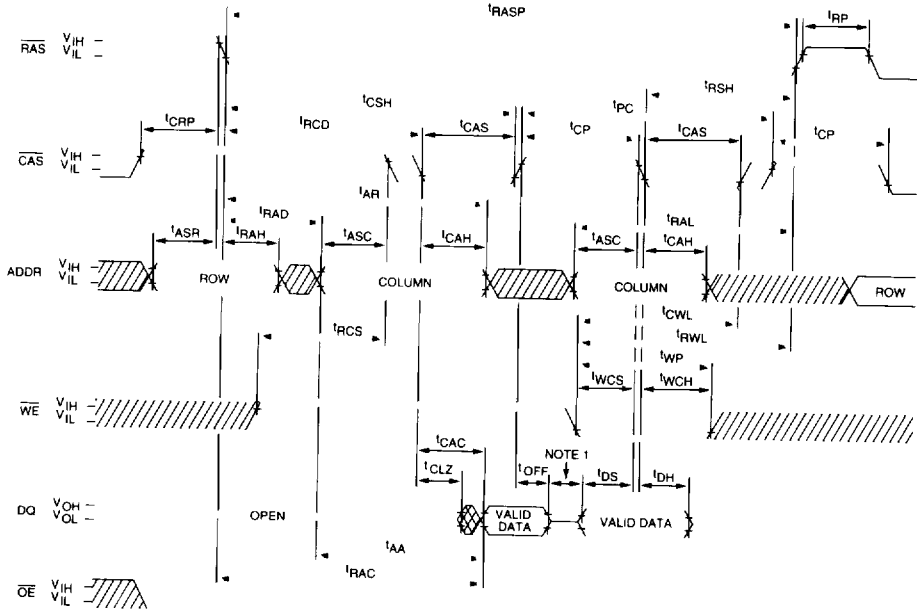




TIMING PARAMETERS

SYM	-6		-7		UNITS	SYM	-6		-7		UNITS
	MIN	MAX	MIN	MAX			MIN	MAX	MIN	MAX	
t _{AA}		30		35	ns	t _{OE}		15		20	ns
t _{AR}	45		50		ns	t _{OEH}	15		20		ns
t _{ASC}	0		0		ns	t _{RAC}		60		70	ns
t _{ASR}	0		0		ns	t _{RAD}	15	30	15	35	ns
t _{AWD}	55		65		ns	t _{RAH}	10		10		ns
t _{CAC}		15		20	ns	t _{RAL}	30		35		ns
t _{CAH}	10		15		ns	t _{RAS}	60	10,000	70	10,000	ns
t _{CAS}	15	10,000	20	10,000	ns	t _{RCD}	20	45	20	50	ns
t _{CLZ}	0		0		ns	t _{RCS}	0		0		ns
t _{CRP}	10		10		ns	t _{RP}	40		50		ns
t _{CSH}	60		70		ns	t _{RSH}	15		20		ns
t _{CWD}	40		50		ns	t _{RWC}	150		180		ns
t _{CWL}	15		20		ns	t _{RWD}	90		100		ns
t _{DH}	10		15		ns	t _{RWL}	15		20		ns
t _{DS}	0		0		ns	t _{WP}	10		15		ns
t _{OD}	3	15	3	20	ns						

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FAST-PAGE-MODE READ-EARLY-WRITE CYCLE



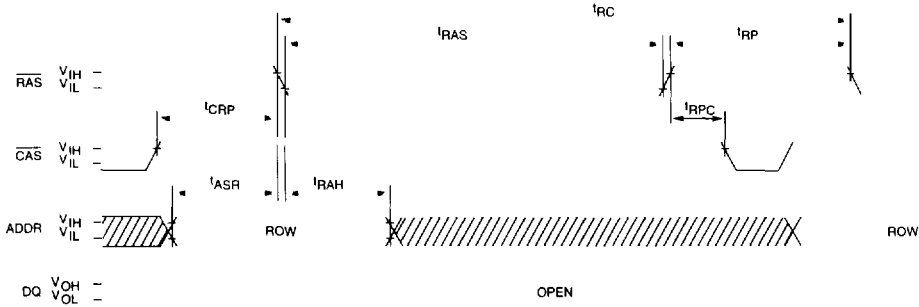
 DON'T CARE
 UNDEFINED

NOTE: 1. Do not drive data prior to tristate.

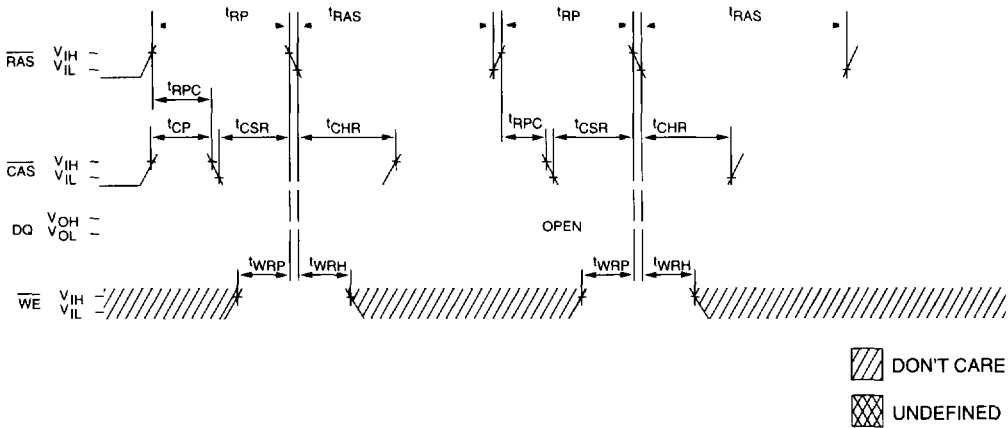
TIMING PARAMETERS



SYM	-6		-7		UNITS	SYM	-6		-7		UNITS
	MIN	MAX	MIN	MAX			MIN	MAX	MIN	MAX	
tAA		30		35	ns	tPC	35		40		ns
tAR	45		50		ns	tRAD	15	60	15	70	ns
tASC	0		0		ns	tRAH	10	30	10	35	ns
tASR	0		0		ns	tRAL	30		35		ns
tCAC		15		20	ns	tRASP	60	100,000	70	100,000	ns
tCAH	10		15		ns	tRCD	20	45	20	50	ns
tCAH	10		15		ns	tRCS	0		0		ns
tCAS	15	10,000	20	10,000	ns	tRP	40		50		ns
tCLZ	0		0		ns	tRSH	15		20		ns
tCP	10		10		ns	tRWL	15		20		ns
tCRP	10		10		ns	tWCH	10		15		ns
tCSH	60		70		ns	tWCS	0		0		ns
tCWL	15		20		ns	tWP	10		15		ns
tDH	10		15		ns						
tDS	0		0		ns						
tOFF	3	15	3	20	ns						

RAS-ONLY REFRESH CYCLE
(\overline{WE} = DON'T CARE)



CBR REFRESH CYCLE
(Addresses and \overline{OE} = DON'T CARE)



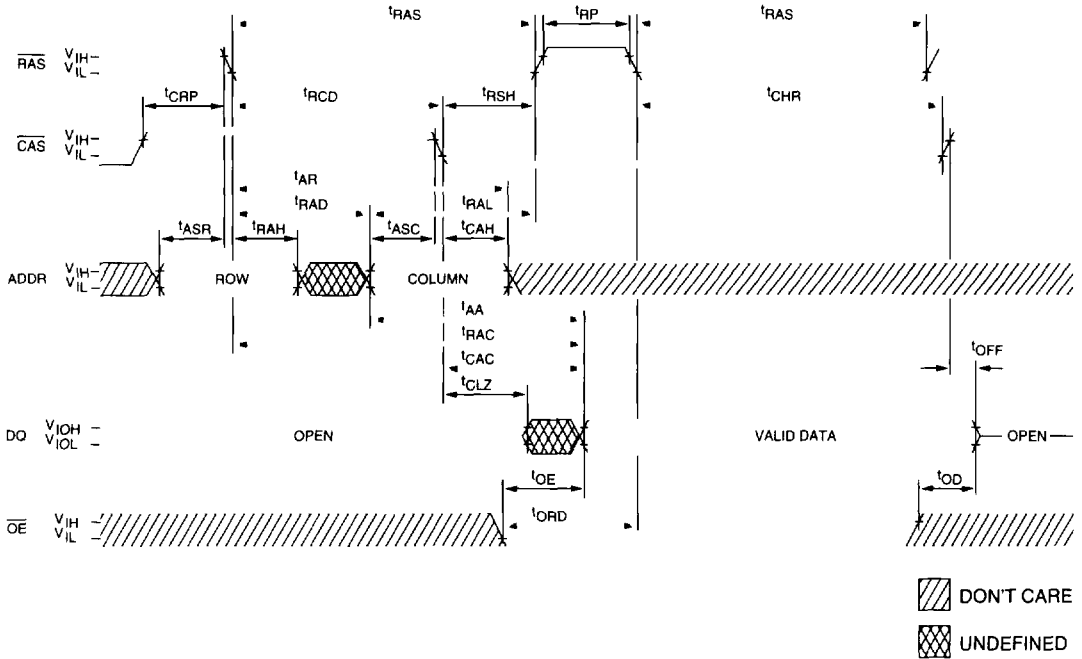
 DON'T CARE
 UNDEFINED

TIMING PARAMETERS

SYM	-6		-7		UNITS	SYM	-6		-7		UNITS
	MIN	MAX	MIN	MAX			MIN	MAX	MIN	MAX	
t _{ASR}	0		0		ns	t _{RAS}	60	10,000	70	10,000	ns
t _{CHR}	10		10		ns	t _{RC}	110		130		ns
t _{CP}	10		10		ns	t _{RP}	40		50		ns
t _{CRP}	10		10		ns	t _{RPC}	0		0		ns
t _{CSR}	10		10		ns	t _{WRH}	10		10		ns
t _{RAH}	10		10		ns	t _{WRP}	10		10		ns

FPM DRAM

HIDDEN REFRESH CYCLE²³
(WE = HIGH; OE = LOW)



TIMING PARAMETERS

SYM	-6		-7		UNITS	SYM	-6		-7		UNITS
	MIN	MAX	MIN	MAX			MIN	MAX	MIN	MAX	
tAA		30		35	ns	tOFF	3	15	3	20	ns
tAR	45		50		ns	tORD	0		0		ns
tASC	0		0		ns	tRAC		60		70	ns
tASR	0		0		ns	tRAD	15	30	15	35	ns
tCAC		15		20	ns	tRAH	10		10		ns
tCAH	10		15		ns	tRAL	30		35		ns
tCHR	10		10		ns	tRAS	60	10,000	70	10,000	ns
tCLZ	0		0		ns	tRCD	20	45	20	50	ns
tCRP	10		10		ns	tRP	40		50		ns
tOD	3	15	3	20	ns	tRSH	15		20		ns
tOE		15		20	ns						